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Examiner
Chun-Kuan (Mike) Lee

Applicant(s)/Patent under Reexamination

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Art Unit

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SEARCHED					
Class	Subclass	Date	Examiner		
710	26	3/27/2007	CHUN- KUAN Lee		
711	118-120	3/27/2007			
711	129	3/27/2007			
711	137	3/27/2007			
711	140	3/27/2007	1.		

INTERFERENCE SEARCHED					
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(INCLUDING SEARCH	DATE	EXMR
(EAST) US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB Inventor search on PALM and eDAN	3/27/2007	CHUN- KUAN Lee
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